

<b>Notice of References Cited</b>	Application/Control No. 09/880,070	Applicant(s)/Patent Under Reexamination TSUDA, HIROSHI	
	Examiner Etienne P LeRoux	Art Unit 2171	Page 1 of 1

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	B	US-6,212,517	04-2001	Sato et al.	707/5
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	K	US-			
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	M	US-			

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